

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 2038-323		U.S. PATENT APPLICATION NO. 10/764,589	
				APPLICANT Takaaki SHIMADA <i>et al.</i>			
				FILING DATE January 27, 2004		GROUP 3761	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
MH ↓ V	5171239	12-1992	Igaue <i>et al.</i>				
	5575783	11-1996	Clear <i>et al.</i>				
	5745922	05-1998	Rajala <i>et al.</i>				
	5846232	12-1998	Serbiak <i>et al.</i>				
	6049916	04-2000	Rajala <i>et al.</i>				
	6595976	07-2003	Jitoe <i>et al.</i>				
	2002/0049421	04-2002	Hayase <i>et al.</i>				
	6297424	10-2001	Olson <i>et al.</i>				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
MH ↓ V	1184012	03-2002	Europe			X	
	1997-38134	02-1997	Japan			X	
	11-299829	11-1999	Japan			X	
	09-099006	04-1997	Japan			X	
	2000-107225	04-2000	Japan			X	
	2003-038556	02-2003	Japan			X	
	09-056747	03-1997	Japan			X	
	2002-095692	04-2002	Japan			X	
	2001-145666	05-2001	Japan			X	
	2001-157690	06-2001	Japan			X	
	08-084747	04-1996	Japan			X	
	0990434	04-2000	Europe			X	
	1157681	11-2001	Europe			X	
	1197195	04-2002	Europe			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

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